FIRST ANNOUNCEMENT—CALL FOR PAPERS

IMPS 2005 ANNUAL MEETING OF THE PSYCHOMETRIC SOCIETY

JULY 5-8, 2005

TILBURG UNIVERSITY, THE NETHERLANDS

The 70th Annual Meeting of the Psychometric Society and the 14th International Meeting of the Psychometric Society (IMPS2005) will be held at Tilburg University, Tilburg, The Netherlands, July 5–8, 2005. Pre-conference workshops will be held Monday, July 4, 2005, with the main conference running from Tuesday to Friday, July 5–8, 2005.

Persons interested in organizing a symposium should contact Ulf Böckenholt at ulf.bockenholt@mcgill.ca.

Persons wishing to present talks (contributing sessions or poster sessions) should send titles and abstracts of no more than 200 words. Abstracts should be e-mailed to "pmetrika@uncg.edu." The subject header of the e-mail should include a reference to IMPS2005.

The following information should be included in attachment:
E-mail address for contact person
Name, institutional affiliation, mailing address, and e-mail address for each author
Name of the presenter of the submission
Type of submission (Contributing or Poster session)
Title of submission
Topic area of submission (see list below)
Abstract (< 200 words)
The attached file should be in text format (.doc, .rtf, .txt).

References should not be included with abstracts.

Each person is permitted to present at most one contributed paper. This restriction does not prevent a keynote speaker or an invited speaker from also presenting one contributed paper, nor does it limit the number of papers on which one can be listed as a coauthor.

The deadline for abstract submission is March 1, 2005. You will be notified by March 31 whether your presentation is accepted.

Topic area choices are (AAP) Applications, (BSI) Bayesian Statistical Inference, (CDA) Categorical Data Analysis, (CTT) Classical Test Theory, (CCC) Classification, Clustering, and Correspondence Analysis, (EDA) Exploratory Data Analysis, (FAC) Factor Analysis, (GRM) Graphical Models, (IRT) Item Response Theory, (GLM) Generalized Linear Models, (LDA) Longitudinal Data Analysis, (MDS) Multidimensional Scaling, (MVA) Multivariate Analysis, (ODS) Optimal/Dual Scaling, (SEM) Structural Equation Modeling, (VCA) Variance Components Analysis, (OTR) Others (please specify)

Further details will be posted on the Society's website as they become available: http://www.psychometrika.org/meeting/2005/index.html

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